#### Update on analysis of beam-test results comparison v2 and v3 geometries

D.Peresunko NRC "Kurchatov institute"

### Data analyzed

MC

Single electron simulation

direction  $\eta=0$ ,  $\phi=270^{\circ}$ 

- vertex just in front of center of

pt 290 MeV,

#### **Data**

- Kindly provided by Viacheslav Kulikov
- Electron beam 293 MeV
- Prototype 6\*8 towers
- 14000 events



### Choice of incidence position



MC simulations, geometry v3



Cross appears when cluster multiplicity is low and corresponds to the center of tower.

Choose incident position to have same distribution: electron primary vertex: (9.5, -168., 13.0)

# Comparison of energy resolution



**Beam-test**: sum of energies of all towers in event with  $E_i > 100 \text{ ADC}(1.43 \text{ MeV})$  $\sigma = 22.6 \text{ MeV}*$ 

MC, digits sum: sum of all energy depositions in event above threshold (1.4 MeV)

**σ=18.1 MeV\*\*** 

MC, clusters: standard clusterization applied.  $E_{min}$ =1.5 MeV,  $E_{seed}$ =10 MeV, Digits with common edges added to cluster, common vertex not sufficient.  $\sigma$ =21.1 MeV

\*Fit with Gaus in range 0.22-0.35 \*\*MC calibration fixed to reproduce mean

Some electronic noise/digitization/... should be added to MC. To check energy dependence of resolution, BT at several energies is necessary.

### Energy resolution: dependence on hit position



Test mean energy and resolution vs. beam incidence position.

Zero: incidence into the center of tower, then moving along z axis and along diagonal.

> Very minor dependence of mean energy (nonlinearity) ~0.5% Small dependence of resolution ~2%.



### Energy resolution: varying light yield



**Beam-test**: sum of energies of all towers in event with  $E_i > 100 \text{ ADC}(1.43 \text{ MeV})$  $\sigma = 22.6 \text{ MeV}$ 

MC, no simulation of light collection: σ=18.1 MeV

MC, simulation of light collection, 40 photons/MeV: σ=18.7 MeV

MC, LY on, 4 photons/MeV: σ=19.5 MeV

MC, LY on, 1 photon/MeV: σ=24.4 MeV

### **Position resolution**



$$x = \frac{\sum x_i w_i}{\sum w_i}$$

$$w_i = Max(0, 3 + log(E_i/E_{tot}))$$

**Beam-test**: use all towers in event with E<sub>i</sub>>100 ADC(1.43 MeV)

**MC, digits sum**: use all energy depositions in event above threshold (1.4 MeV)

Position resolutions are close, but shape in beam-test is different and asymmetric.

## Conclusions

- Moving electron vertex in MC from the edge of EMC improved energy resolution
- Now energy resolution in MC without LY simulation and electronic noise is smaller than in beamtest
- Agreement can be reached both by adjusting LY and noise simulation, need another energy to fix
- Position resolution is similar, but because of asymmetry of beamtest results hard to make quantitative comparison.